

# Delgermaa Nergui

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/4377776/publications.pdf>

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10  
papers

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1684188

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1474206

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#	ARTICLE	IF	CITATIONS
1	Response of Integrated Silicon Microwave <i>pin</i> Diodes to X-Ray and Fast-Neutron Irradiation. IEEE Transactions on Nuclear Science, 2022, 69, 282-289.	2.0	0
2	Single-Event Transients in a Commercially Available, Integrated Germanium Photodiode for Silicon Photonic Systems. IEEE Transactions on Nuclear Science, 2022, 69, 527-533.	2.0	1
3	Total-Ionizing-Dose Response of SiGe HBTs at Elevated Temperatures. IEEE Transactions on Nuclear Science, 2022, 69, 1079-1084.	2.0	1
4	Comparison of Single-Event Transients in SiGe HBTs on Bulk and Thick-Film SOI. IEEE Transactions on Nuclear Science, 2020, 67, 71-80.	2.0	7
5	New Approach for Pulsed-Laser Testing That Mimics Heavy-Ion Charge Deposition Profiles. IEEE Transactions on Nuclear Science, 2020, 67, 81-90.	2.0	16
6	Electronic-to-Photonic Single-Event Transient Propagation in a Segmented Mach-Zehnder Modulator in a Si/SiGe Integrated Photonics Platform. IEEE Transactions on Nuclear Science, 2020, 67, 260-267.	2.0	3
7	Single-Event Transients in SiGe HBTs Induced by Pulsed X-Ray Microbeam. IEEE Transactions on Nuclear Science, 2020, 67, 91-98.	2.0	4
8	Optimizing Optical Parameters to Facilitate Correlation of Laser- and Heavy-Ion-Induced Single-Event Transients in SiGe HBTs. IEEE Transactions on Nuclear Science, 2019, 66, 359-367.	2.0	15
9	Using Bessel beams and two-photon absorption to predict radiation effects in microelectronics. Optics Express, 2019, 27, 37652.	3.4	9
10	SiGe HBT Profiles With Enhanced Inverse-Mode Operation and Their Impact on Single-Event Transients. IEEE Transactions on Nuclear Science, 2018, 65, 399-406.	2.0	9